

<b>Notice of References Cited</b>	Application/Control No. 10/553,684	Applicant(s)/Patent Under Reexamination YATABE, FUMIO	
	Examiner Hai H. Huynh	Art Unit 3747	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0180126 A1	08-2006	Hattori, Shogo	123/494
	B	US-			
	C	US-			
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	E	US-			
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